

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination LEE ET AL.	
		Examiner JOHN F. MORTELL	Art Unit 2612	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,835,028 A	11-1998	Bender et al.	340/937
*	B	US-6,226,592 B1	05-2001	Luckscheiter et al.	701/301
*	C	US-2003/0004617 A1	01-2003	Kimura et al.	701/1
*	D	US-2003/0045973 A1	03-2003	Okamoto, Shinichi	701/1
*	E	US-2003/0058337 A1	03-2003	Tanaka et al.	348/116
*	F	US-6,564,122 B1	05-2003	Huertgen et al.	701/1
*	G	US-6,587,760 B2	07-2003	Okamoto, Shinichi	701/1
*	H	US-2004/0153243 A1	08-2004	Shimazaki et al.	701/300
*	I	US-6,825,880 B2	11-2004	Asahi et al.	348/333.02
*	J	US-6,871,717 B2	03-2005	Kada, Tomoyasu	180/167
*	K	US-6,919,917 B1	07-2005	Janssen, Holger	348/143
*	L	US-6,919,822 B2	07-2005	Tanaka et al.	340/932.2
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

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